<News Release> New Processing-In-Memory Technology for Next-Generation AI Chips

e-AI business operation department Industrial Solution Planning & Strategy division, IBU Renesas Electronics

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2019 Symposia on VLSI Technology and Circuits.

Oral presentation

- Date: at 9:20am on 13th June (JST)
- Session: Technology and System for AI

Title: "A Ternary Based Bit Scalable, 8.80 TOPS/W CNN Accelerator with Multi-Core Processing-in-Memory Architecture with 896K Synapses/mm²"

Demonstration

Date:5:30pm on 10th June (JST)Session:Demo Session & Reception



RENESAS e-AI (embedded-AI)



OT Applications are expanding with e-AI Difference between cloud AI and e-AI on OT



e-AI: Specific to Inference for End-point Concept release in 2015; e-AI tools introduced in July 2017



DRP Accelerates e-AI Roadmap 10 Times the Performance Per 1.5 Years

e-AI Capability



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Power Efficiency of e-AI



DRP realizes both flexibility and power efficiency

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Technical Details



Overview of the News on 13th June

Renesas Electronics Develops New Processing-In-Memory Technology for Next-Generation AI Chips and Demonstrates AI Processing Performance of 8.8 TOPS/W

AI Accelerator Achieves Both CNN Processing Speeds and Reduced Power Consumption

Renesas Electronics has developed an AI accelerator that performs CNN (convolutional neural network) processing at high speeds and low power to move towards the next generation of Renesas embedded AI (e-AI). A test chip featuring this accelerator has achieved the power efficiency of 8.8 TOPS/W – the industry's highest class of power efficiency.

The accelerator is based on the processing-in-memory (PIM) architecture and features three new developments:

- 1. Ternary-valued (-1, 0, 1) SRAM structure PIM technology that can perform large-scale CNN computations.
- 2. SRAM circuit to be applied with comparators that can read out memory data at low power.
- 3. Technology that prevents calculation errors due to process variations in the manufacturing.

These technologies achieve both a reduction in the memory access time in deep learning processing and a reduction in the power required for the multiply-and-accumulate operations, while maintaining an accuracy ratio of over 99 percent when evaluated in a handwritten character recognition test (MNIST).

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Opportunities for Class-4 e-AI

- The new technology could be **one of the key technologies** to realize **e-AI Class-4 (10 TOPS/W class)** performance

- To realize e-AI Class-4 (10 TOPS/W class) performance, two issues need to be achieved: 1) **A reduction in the memory access time** and 2) **a reduction in the power for the multiply-and-accumulate operations** in deep learning processing.

Technology Architecture

- Advanced SRAM structure PIM technology is applied.

- PIM architecture enables "multiply-and-accumulate operations in the memory circuit as data is read out from that memory."



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Processing-in-Memory (Circuit Principle)

MAC (Multiply-and-Accumulate) operations in the memory circuit as data is read out from that memory, which enables a reduction of both the memory access time and power consumption.



PIM Challenges

Traditional SRAM structure PIM technology:

- 1 bit (binary (0, 1)) calculation is basis.
- Calculation bit number is up to bit number of cell.
- Process variation occurs the errors of MAC results.



Ternary-Valued SRAM Structure PIM Technology That Can Perform Large-Scale CNN Computations

- Ternary SRAM-based (-1, 0, 1) PIM architecture allows switching the number of bits between, for example, 1.5-bit (ternary) and 4-bit calculations, according to the required accuracy.



Low-Power Memory Data Readout Circuit That Combines Comparators and Replica Cells

- High-accuracy memory readout circuits without using area- and power-consuming A/D converters.
- The number of activated nodes (neurons) in neural network is very small; lower power operation is achieved by stopping operation of the readout circuits for inactive nodes.



Low-Power Memory Data Readout Circuit Cont.

In order to measure ternary memory cell current with comparators, current comparison between ternary memory cells and replica cells, in which the current can be controlled flexibly, is iterated by bit serial.



Technology That Prevents Calculation Errors Due to Process Variations in the Manufacturing

- Activated nodes are allocated selectively to SRAM calculation blocks that have minimal manufacturing process variations.
- Accurate calculation can be evaluated without additional circuits in SRAM macros, such as redundant cell arrays.



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Test Chip Overview



4 clusters incorporated, which is equivalent to CPU core ->4 kinds of AI processing can be executed simultaneously



SRAM [Mb]

12.58

Test Chip Evaluation Results

- An accuracy ratio of more than 99 percent when evaluated in a handwritten character recognition test (MNIST). - Calculation errors is reduced to a level where they can be essentially ignored



Performance Comparison

In this work, both bit scalability and power efficiency are highly established compared with prior works

 $\star \star$ Extremely superior \star Superior \triangle Same level \times Inferior

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	Digital Architecture				Processing-in-Memory						
	ISCA '16		ISSCC '18			ISSCC '18		VLSI '18		Our chip	
Process node (nm)		28 (Sim.)		40		65		65		12	
Bit number (Scalability)	*	4bit	*	1-4bit	\triangle	1bit	\triangle	1bit	* *	1.5-4bit	
On-chip memory available for calculation	*	41MB	*	7.6MB	×	10Kb PIM (not adequate)	×	2Mb PIM 8KB SRAM (not adequate)	*	4Mb PIM 1.5MB SRAM	
Power efficiency @NAM macro		No data		No data	*	28.1 TOPS/W	**	658 TOPS/W	*	79.3 TOPS/W	
Power efficiency @system	*	4.1 TOPS/W (Sim.)	\bigtriangleup	2.2 TOPS/W (1bit)	×	not evaluated	×	not evaluated	* *	8.8 TOPS/W (Ternary)	

APPENDIX

Demonstration Overview

Renesas is demonstrating real-time image recognition using a prototype AI module in which the test chip, powered by small battery, are connected with a microcontroller, a camera and other peripheral devices and combined with development tools.







